SCAS461D - FEBRUARY 1995 - REVISED DECEMBER 1996

- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

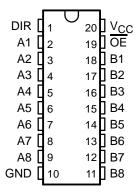
#### description

The 'AC245 octal bus transceivers are designed for asynchronous two-way communication between data buses. The control-function implementation minimizes external timing requirements.

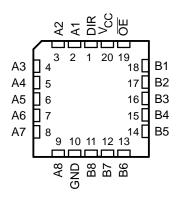
When the output-enable  $(\overline{OE})$  is low, the device passes noninverted data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction control (DIR) input. A high on  $\overline{OE}$  disables the device so that the buses are effectively isolated.

The SN54AC245 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AC245 is characterized for operation from -40°C to 85°C.

SN54AC245 . . . J OR W PACKAGE SN74AC245 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



# SN54AC245 . . . FK PACKAGE (TOP VIEW)



#### **FUNCTION TABLE**

INP	UTS	ODEDATION
ŌĒ	DIR	OPERATION
L	L	B data to A bus
L	Н	A data to B bus
Н	Х	Isolation



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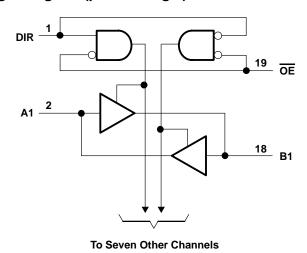
EPIC is a trademark of Texas Instruments Incorporated.



#### logic symbol†

#### 19 OE 3EN1[BA] 3EN2[AB] 18 В1 $\triangleright$ 2∇ 17 **A2** B2 16 В3 **A3** 15 В4 **A4** 14 Α5 **B5** 13 **B6** Α6 12 8 **B7** 11 **A8 B8**

#### logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>		0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V <sub>O</sub> (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )		±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )		±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )		±50 mA
Continuous current through V <sub>CC</sub> or GND		±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air)(see Note 2):	DB package	0.6 W
	DW package	1.6 W
	N package	1.3 W
	PW package	0.7 W
Storage temperature range, T <sub>stg</sub>		–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## recommended operating conditions (see Note 3)

			SN54A	C245	5 SN74AC245		UNIT
			MIN	MAX	MIN	MAX	UNII
Vcс	Supply voltage		2	6	2	6	V
		V <sub>CC</sub> = 3 V	2.1		2.1		
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15		3.15		V
	V <sub>CC</sub> = 5.5 V	3.85		3.85			
V <sub>IL</sub> Low-level input voltage	V <sub>CC</sub> = 3 V		0.9		0.9		
	V <sub>CC</sub> = 4.5 V		1.35		1.35	V	
	V <sub>CC</sub> = 5.5 V		1.65		1.65		
VI	Input voltage		0	VCC	0	VCC	V
VO	Output voltage		0	VCC	0	VCC	V
		V <sub>CC</sub> = 3 V		-12		-12	
lOH	High-level output current	V <sub>CC</sub> = 4.5 V		-24		-24	mA
		V <sub>CC</sub> = 5.5 V		-24		-24	
IOL Low-level output current		V <sub>CC</sub> = 3 V		12		12	
	Low-level output current	V <sub>CC</sub> = 4.5 V		24		24	mA
		V <sub>CC</sub> = 5.5 V		24		24	
Δt/Δν	Input transition rise or fall rate	<u>.</u>	0	8	0	8	ns/V
T <sub>A</sub>	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

## SN54AC245, SN74AC245 OCTAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		T,	A = 25°C	;	SN54A	C245	SN74A	SN74AC245		
PARAMETER		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
		3 V	2.9			2.9		2.9			
	$I_{OH} = -50 \mu A$	4.5 V	4.4			4.4		4.4			
		5.5 V	5.4			5.4		5.4			
Vou	I <sub>OH</sub> = -12 mA	3 V	2.56			2.4		2.46		_	
VOH	1011 = 24 mA	4.5 V	3.86			3.7		3.76		V	
	I <sub>OH</sub> = -24 mA	5.5 V	4.86			4.7		4.76			
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85					
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85			
	I <sub>OL</sub> = 50 μA	3 V		0.002	0.1		0.1		0.1	V	
		4.5 V		0.001	0.1		0.1		0.1		
		5.5 V		0.001	0.1		0.1		0.1		
V <sub>OL</sub>	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44		
I VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44		
	10L = 24 111A	5.5 V			0.36		0.5		0.44		
	I <sub>OL</sub> = 50 mA <sup>†</sup>	5.5 V					1.65				
	I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V							1.65		
A or B ports‡	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μΑ	
OE or DIR		3.5 V			±0.1		±1		±1	μΑ	
loz	$V_O = V_{CC}$ or GND, $V_I(OE) = V_{IL}$ or $V_{IH}$	5.5 V			±0.5		±10		±5	μΑ	
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ	
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4.5						pF	
C <sub>io</sub>	$V_O = V_{CC}$ or GND	5 V		15						pF	

T Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\,\pm\,$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	չ = 25°C	;	SN54A	C245	SN74A	C245	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
tPLH	A or B	B or A	1.5	5	8.5	1	11.5	1	9	ns
t <sub>PHL</sub>	AOIB		1.5 5 8.5	8.5	1 1	10	1	9	115	
<sup>t</sup> PZH	<del></del>	A or B	2.5	7	11.5	1	13.5	2	12.5	20
tPZL	OE	AUIB	2.5	7.5	12	1	14.5	2	13.5	ns
t <sub>PHZ</sub>		A or P	2	6.5	12	1	13.5	1	12.5	20
t <sub>PLZ</sub>	OE	A or B	2	7	11.5	1	14	1.5	13	ns



<sup>‡</sup> For I/O ports, the parameter IOZ includes the input leakage current.

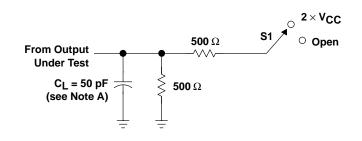
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	SN54A	C245	SN74A	C245	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>PLH</sub>	A or B	B or A	1.5	3.5	6.5	1	8.5	1	7	ne
<sup>t</sup> PHL	AUIB	BULA	1.5	3.5	6	1	7.5	1	7	ns
<sup>t</sup> PZH		A or B	1.5	5	8.5	1	10	1	9	ns
t <sub>PZL</sub>	ŌĒ	AUID	1.5	5.5	9	1	10.5	1	9.5	115
<sup>t</sup> PHZ	-	A or B	1.5	5.5	9	1	10.5	1	10	20
tPLZ	ŌĒ		1.5	5.5	9	1	10.5	1	10	ns

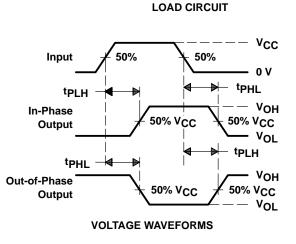
### operating characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C

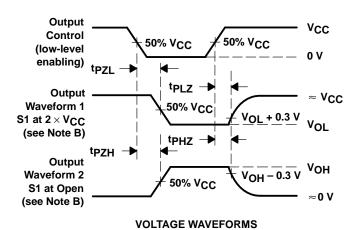
PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance per transceiver	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	45	pF

#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
tPLH/tPHL	Open
tPLZ/tPZL	2×V <sub>CC</sub>
tPHZ/tPZH	Open





NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5$  ns,  $t_f \leq 2.5$  ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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